

Study of vacuum stability at cryogenic temperature

WP4 - Activity at LNF

Alba 07-09/11/2017

Marco Angelucci

Roberto Cimino

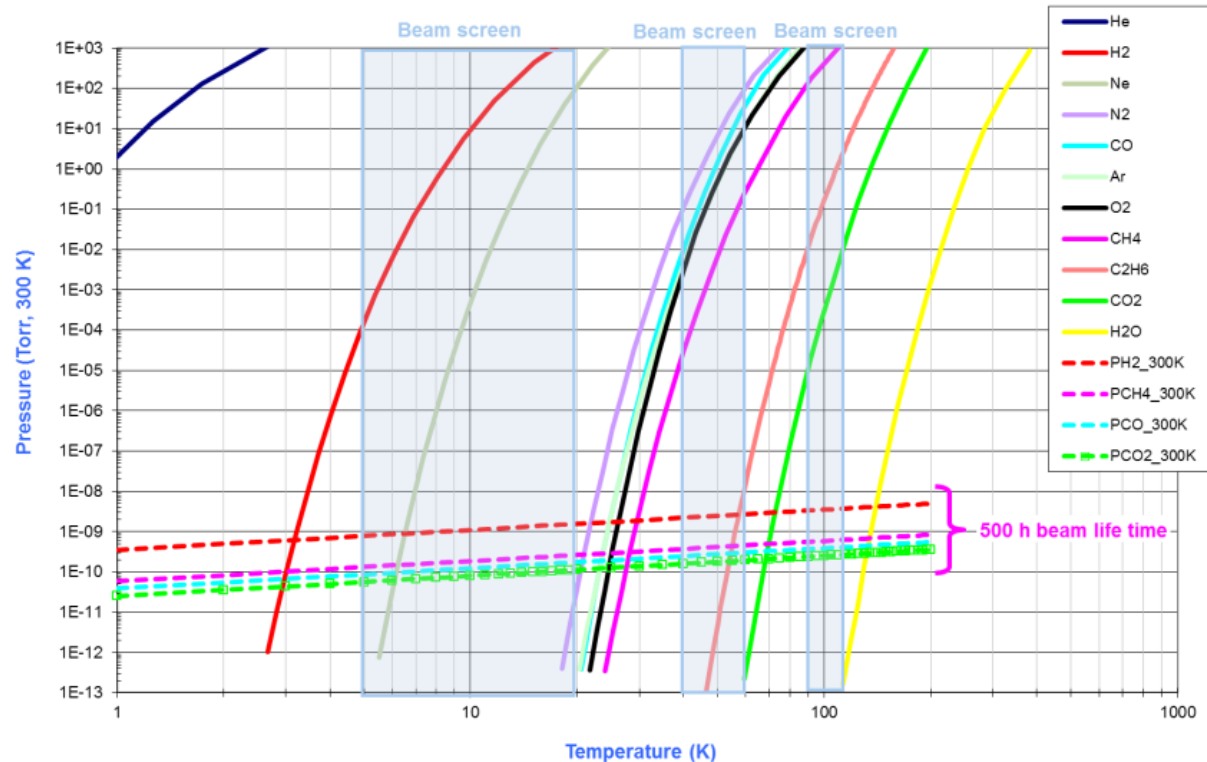
Beam Screen Temperature

Working Pressure $(<10^{-11})$ \longleftrightarrow BS Temperature Range

LHC
SR Power = 0.13 W/m

FCC
SR Power = 40 W/m

Saturated vapour pressure from Honig and Hook (1960) (C2H6 Thibault et al.)

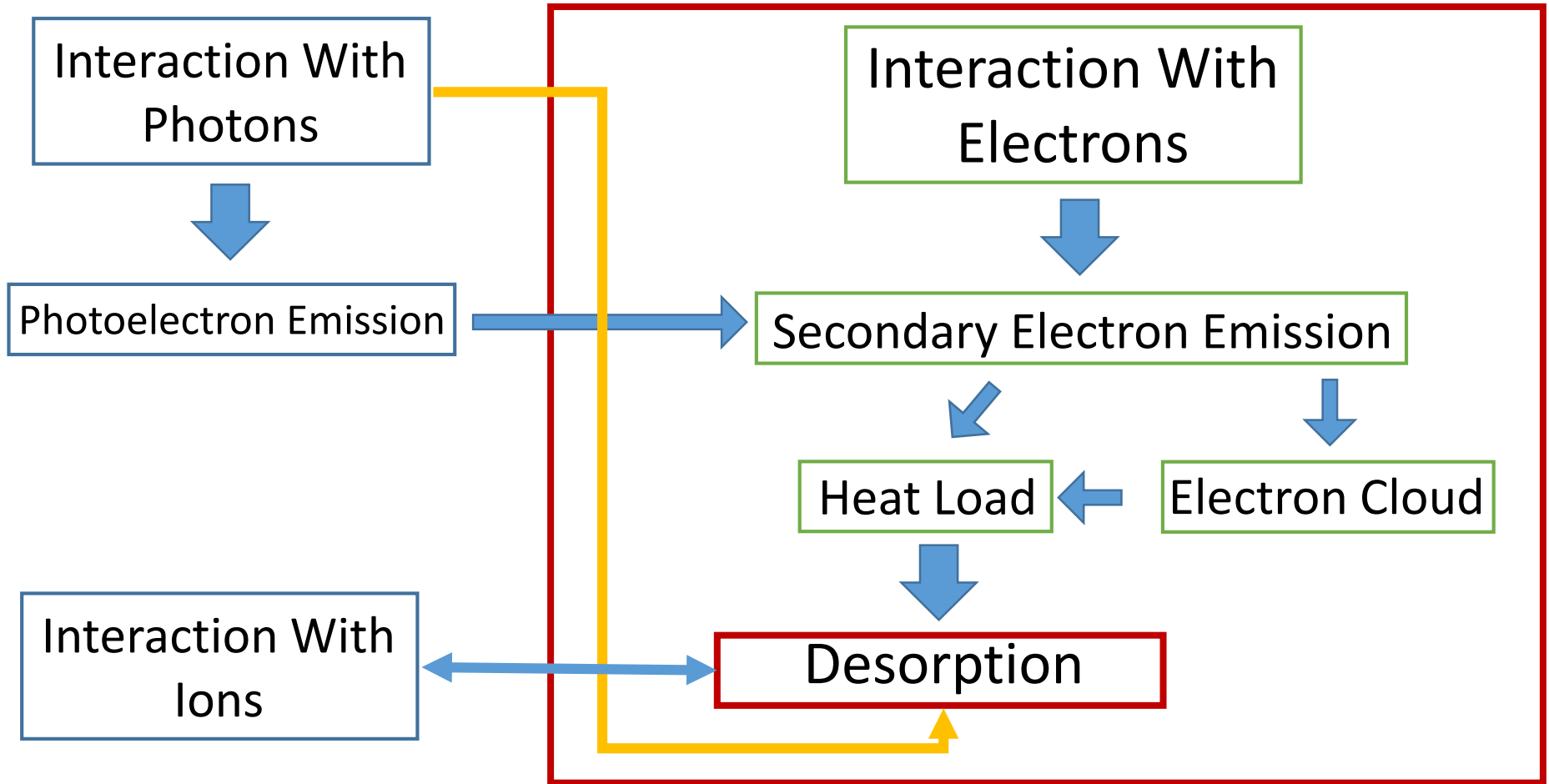


Temperature

- Find right working temperature is a fundamental point for vacuum stability.
- Work near a gas desorption temperature could generate great pressure oscillations.

Study of adsorption/desorption behaviour near critical temperature is mandatory to understand vacuum stability

Vacuum Stability



- Surface Quality

- X-Ray / UV Photoemission
- Secondary Electron Yield (SEY)

- Adsorbed atoms and molecules

- Cryogenic temperature
- Atoms/Molecules Adsorption/Desorption process

LNF-Lab Now

Two Different Ultra-High Vacuum Systems equipped with:

- Low Energy Electron Diffraction
- Secondary Electron Yield Spectroscopy
- Surface Preparation
- Gas-Line

- X-Ray/UV Photoemission
- High Temperature Manipulator

- Low Temperature Manipulator (≈ 9 K)

Raman Spectroscopy

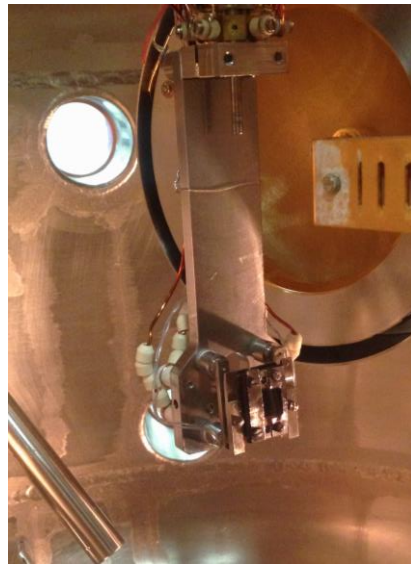
Scanning Tunneling Microscopy

LNF-Lab Now

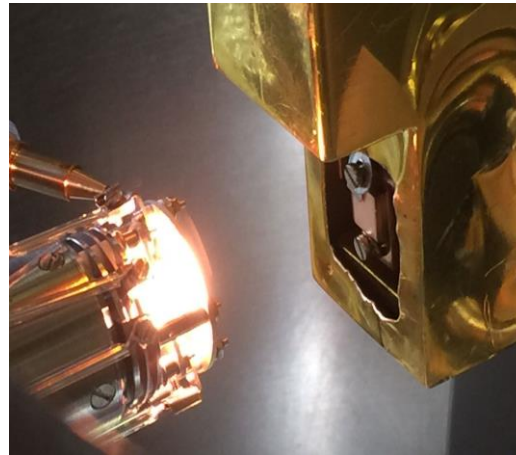
Gas-Line



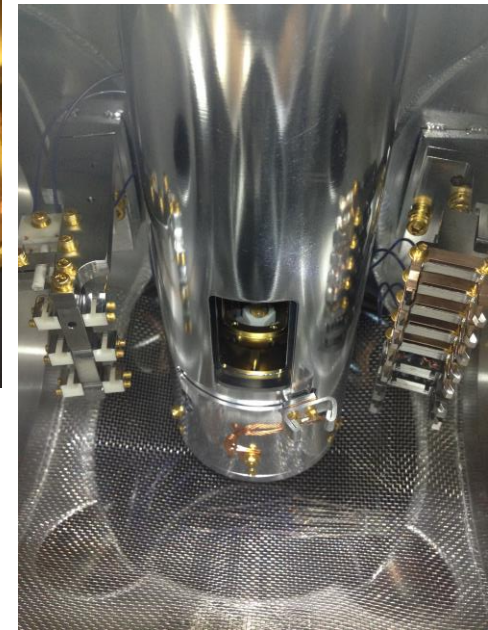
HT Manipulator



LT Manipulator



LT STM

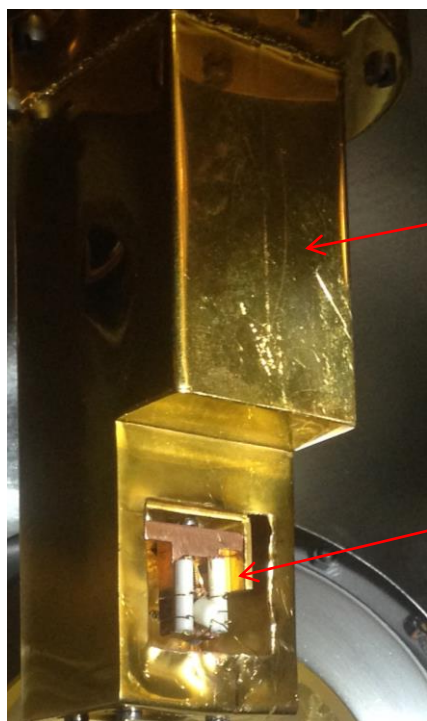


Maintenance of Low Temperature System

Fixed some problems with Low Temperature manipulator, working on compressor of cryogenic system (≈ 5 months)

Now Low Temperature = 10 K

LNF-Lab Activities I

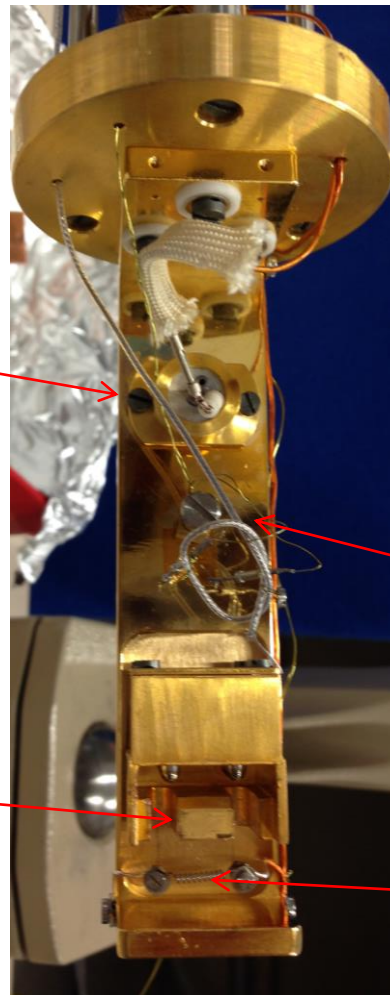


Screen

Sample

Heater

Sample Holder



Temperature Diode

Filament Heater

First Preliminary Results

Adsorption/Desorption process of Atoms and Molecules (Argon, CO) at cryogenic temperature measured with:

Secondary Electron Yield (SEY) and Temperature Programmed Desorption (TPD)

- Adsorption process of Argon (**Ar**) and Carbon-Monoxide (**CO**) on atomically sputtered Cu surface at low temperature (with SEY)
- Desorption process of **Ar** and **CO** from heated Cu sample (with SEY and TPD)
- Interaction between electrons and **Ar** films (SEY)

Working Parameters:

- Basic Pressure $\leq 1 \times 10^{-10}$ mbar
- Electron Beam Current $< 1 \times 10^{-7}$ Ampere (A) (Max Current @ max electron energy)
- Electron Beam Energy from 75 to 1000 eV
- Sample Bias 75 V
- Single Spectra Acquisition Time ≈ 120 sec
- Beam Radius < 1.0 mm

- 1 Langmuir (L) = 1 sec @ 1×10^{-6} mbar
- 1 L = 1 Mono-Layer (ML) (with sticking coefficient = 1)

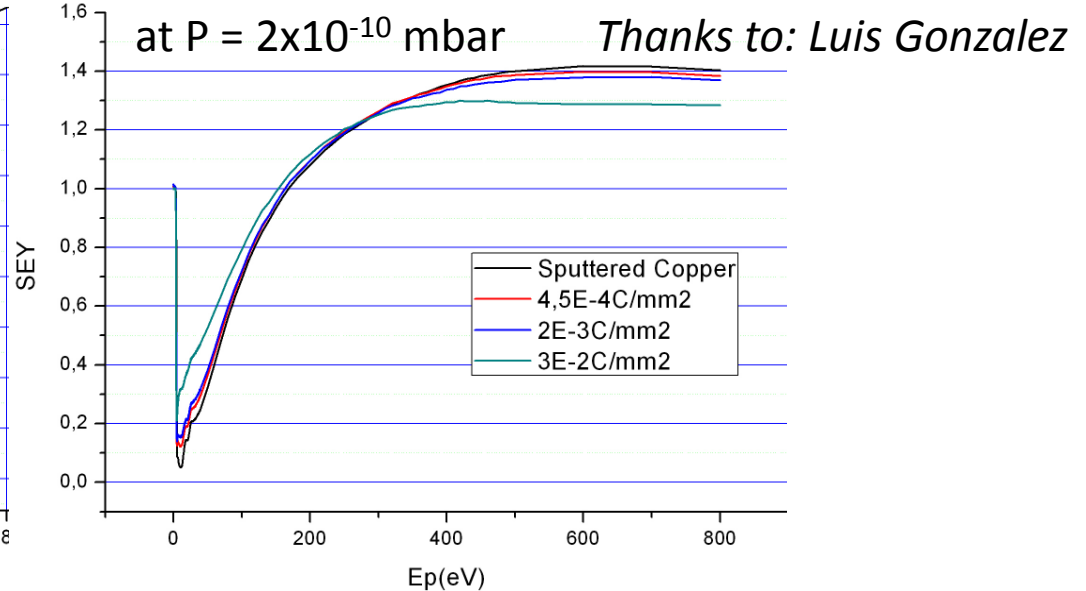
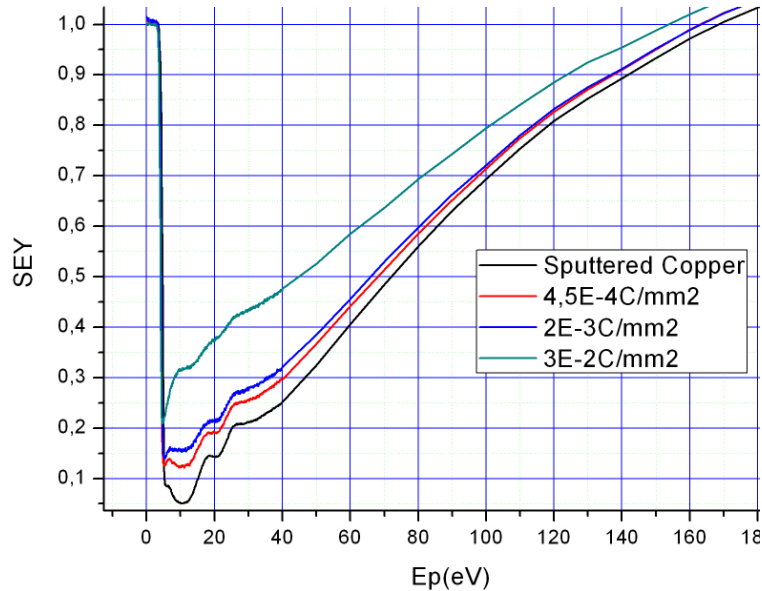
- Temperature range: form 10 to 300 K

- Why start with Atomically Sputtered clean Copper?

Electron Beams have not effect on a clean surface so any modification to the SEY can be attributed to atoms and molecules on surface.

- easy to single out contamination (sample pumping) from experimental.
- easy to eliminate spurious and otherwise occurring scrubbing effects from real non-clean surfaces.

Experimental Test with Atomically Sputtered Copper

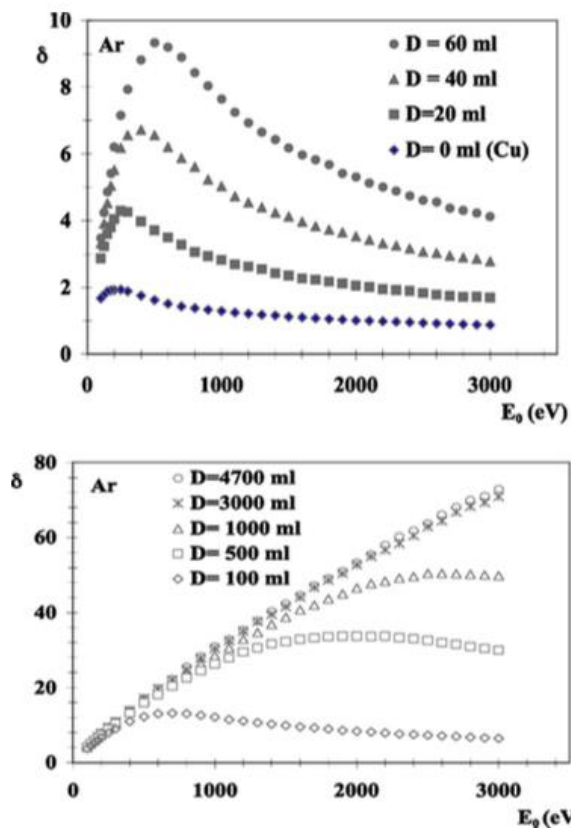


- First observable changes (blue) after $0.02C/mm^2 \rightarrow$ more than 6 h SEY measurements
- More significant changes (green) needs more than 60 h continuous measuring
- Our standard SEY lasts 120s!

- Why Argon and Carbon-Monoxide?

- ① Argon is an inert gas and it's the best starting point to study SEY at Low Temperature
- ① Carbon-Monoxide is a gas of great interest for accelerator physics

Argon

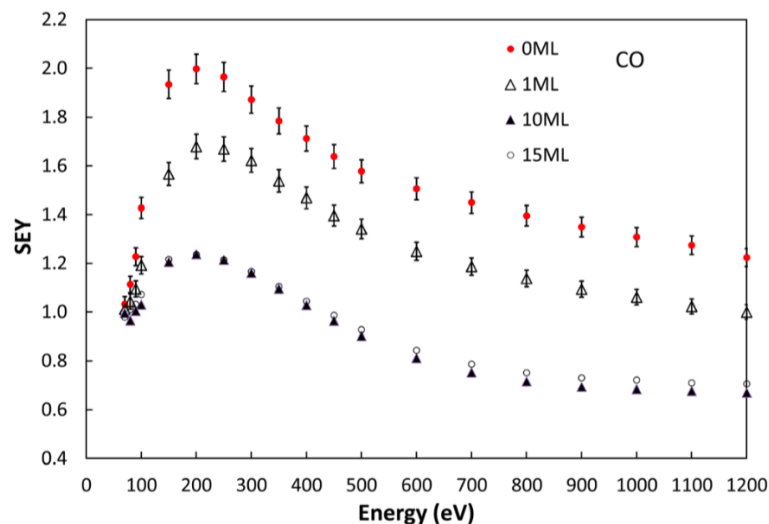


J. Cazaux et al.:

Phys. Rev. B 71 (2005) 035419

Reference Literature spectra of Argon and Carbon-Monoxide SEY

Carbon-Monoxide



A. Kuzucan et al.:

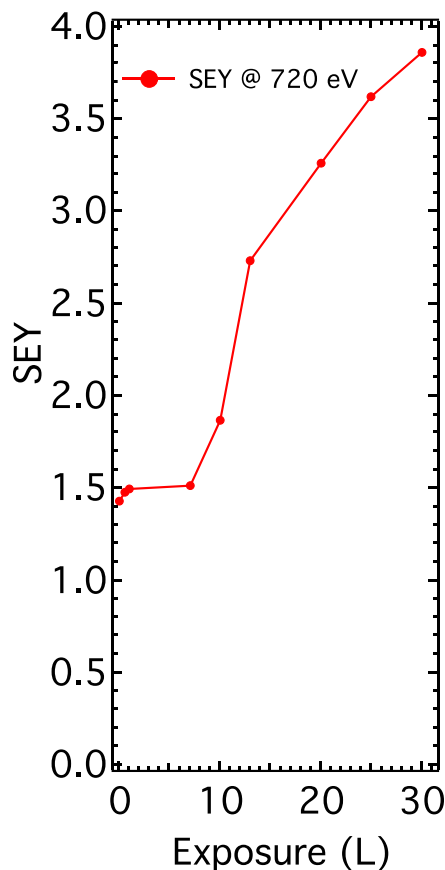
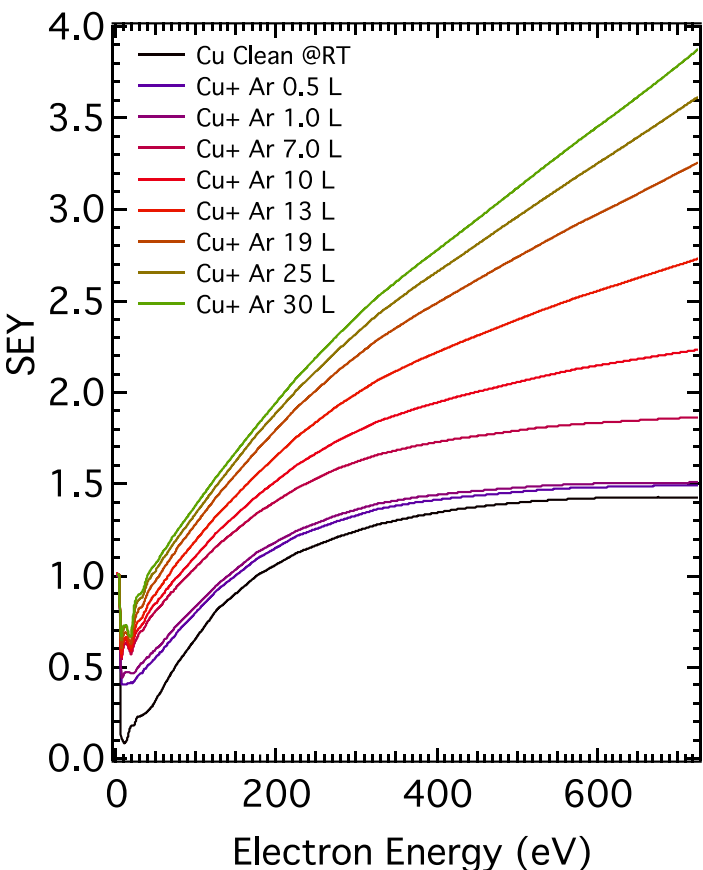
J. of Vacuum Sci. & Tech. A 30 (2012) 051401

First Preliminary Experimental Results

Argon Adsorption (SEY)

Adsorption process of Argon on Cu sample at 10 K

General behaviour



Two different regions

High Energy
(>50 eV)

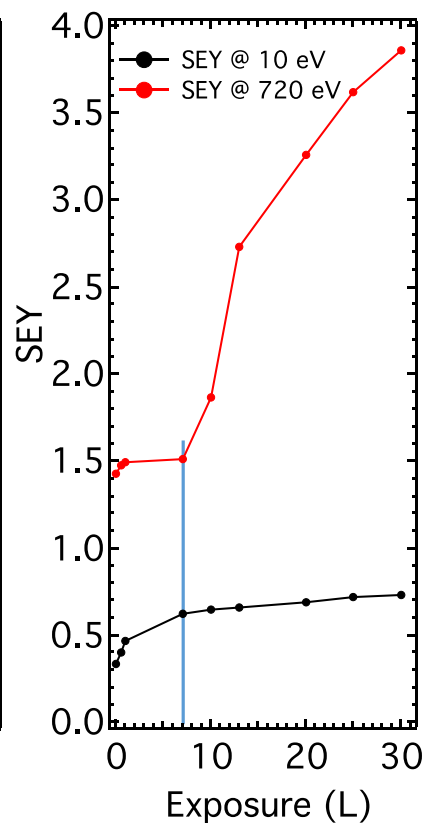
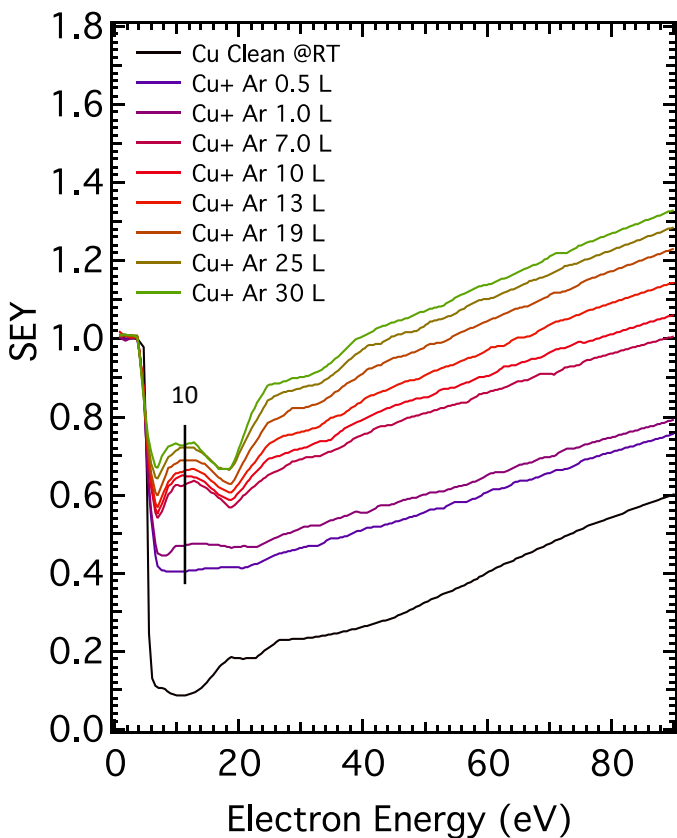
Low Energy
(<50 eV)



- SEY at 720 eV increases during adsorption from **1.4** to **3.9**
- Formation of Argon Thick Film (TF)

Adsorption process of Argon on Cu sample at 10 K

Low Energy behaviour



Two different regions

High Energy
(>50 eV)

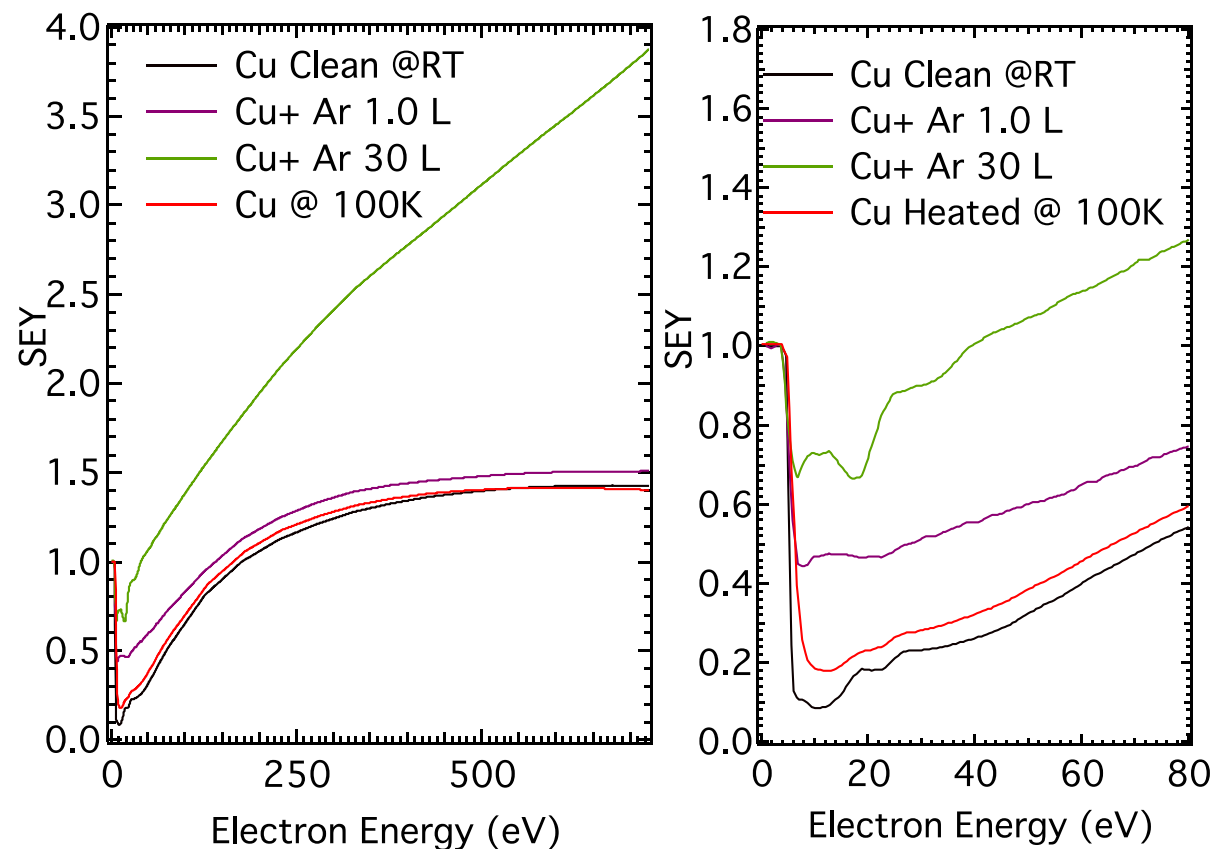
Low Energy
(<50 eV)



- SEY increases during first steps and reaches saturation
- Formation of Argon Single Layer (SL)

Argon Desorption (SEY)

Desorption process: Cu sample heated up to 100 K

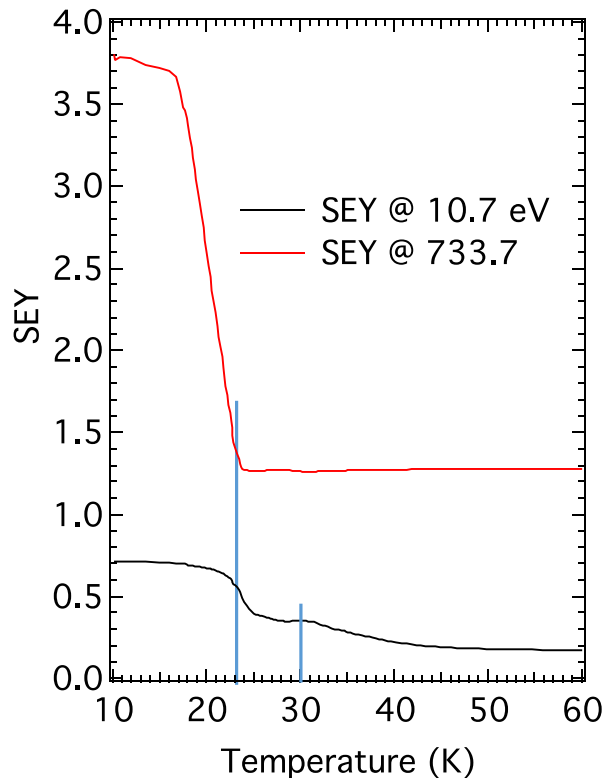
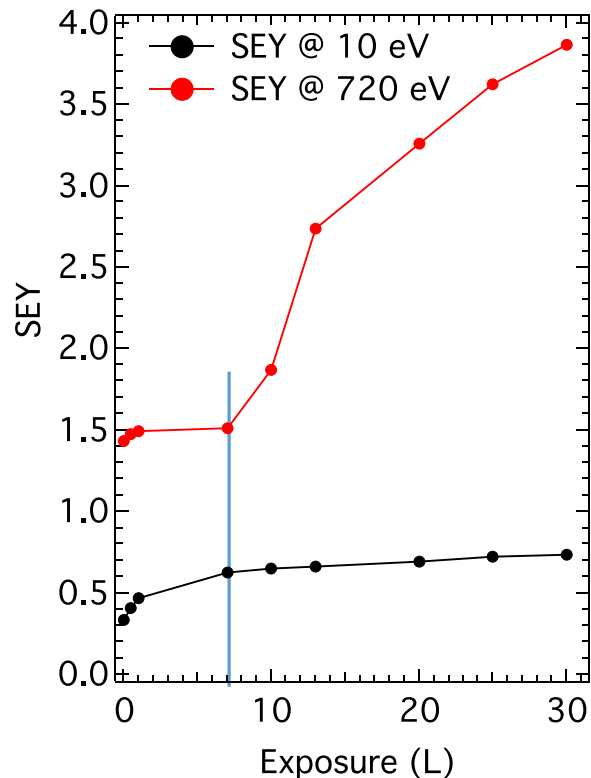


Sample "*Cleaned*"
SEY returns to the initial
value

Slight differences due to
possible residual impurities
on the surface

Argon Desorption (SEY)

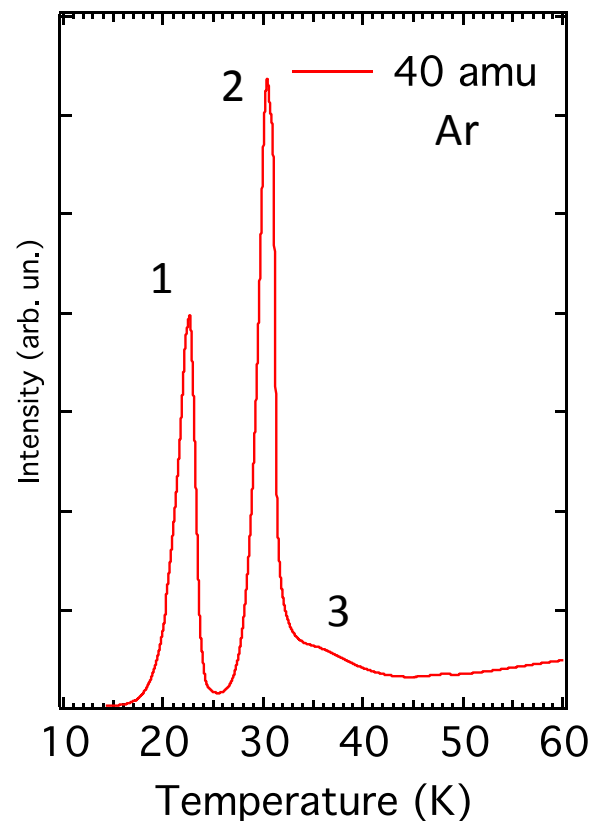
Desorption process heating Cu sample to 100 K



Same behavior in the opposite direction

Argon Desorption (TPD)

Test of Temperature Programmed Desorption (TPD) with Mass Spectrometer



Three different peaks at 22, 30 and 37 K

due to the different desorption of TF from Manipulator (Peak 1 and TF/SL from sample

Argon Results

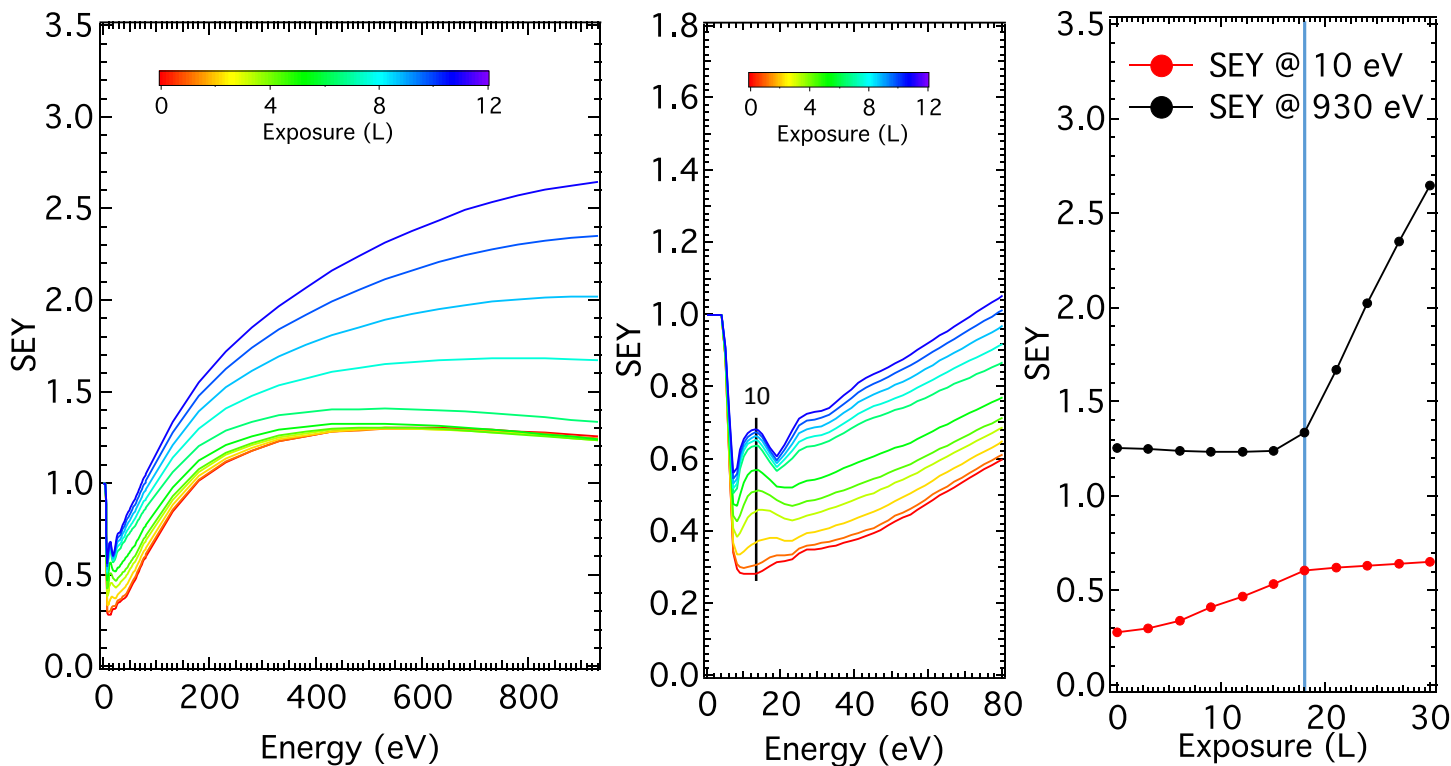
Adsorption Process (LT)

- Formation of a Thick Film (TF) at high coverage (increasing of SEY)
- Formation of a Single Layer (SL) on Cu at LT (characteristic peaks in low energy region)

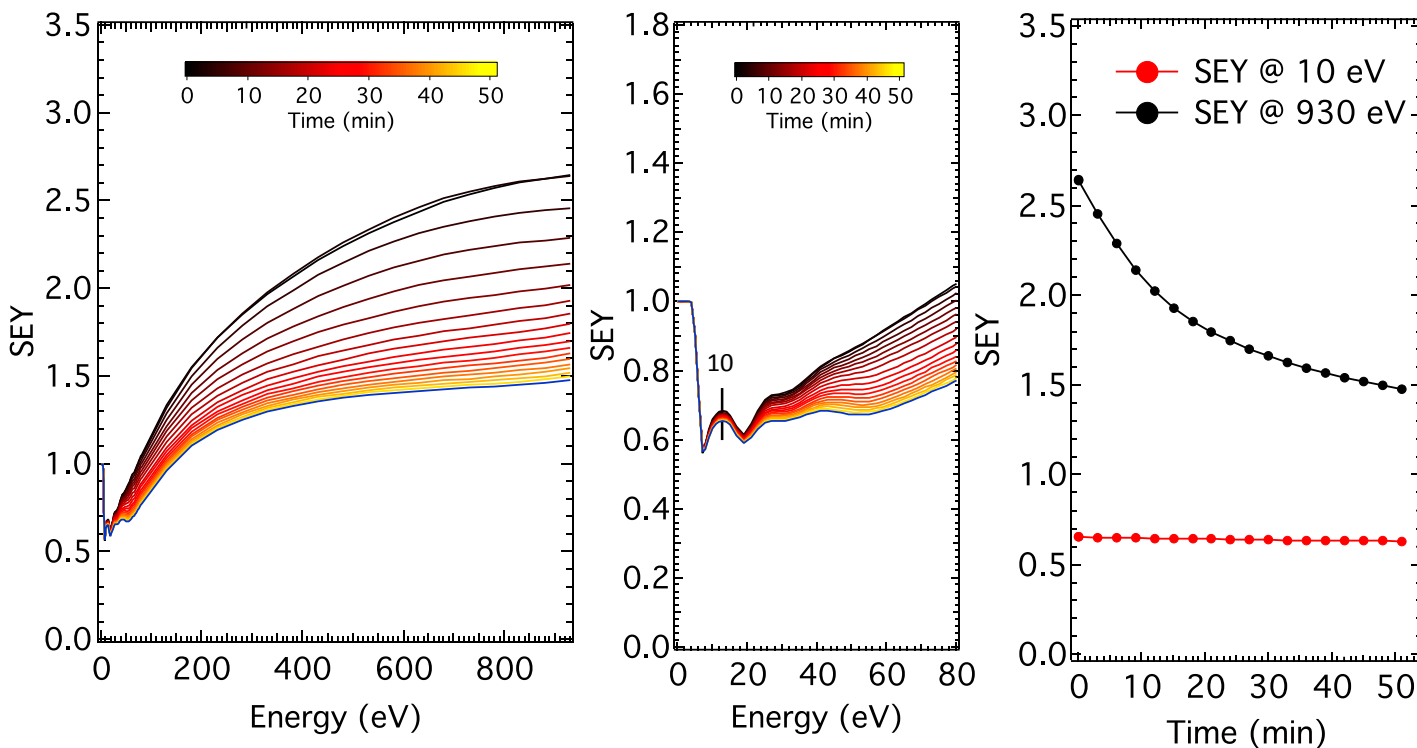
Desorption Process (Heating)

- System returns to the original state with slight differences
 - Possibility to follow formation of SL from TF
- Possibility to measure desorption temperature with SEY and TPD

Second Run of Adsorption process of Argon on Cu sample at 10 K Same General behaviour

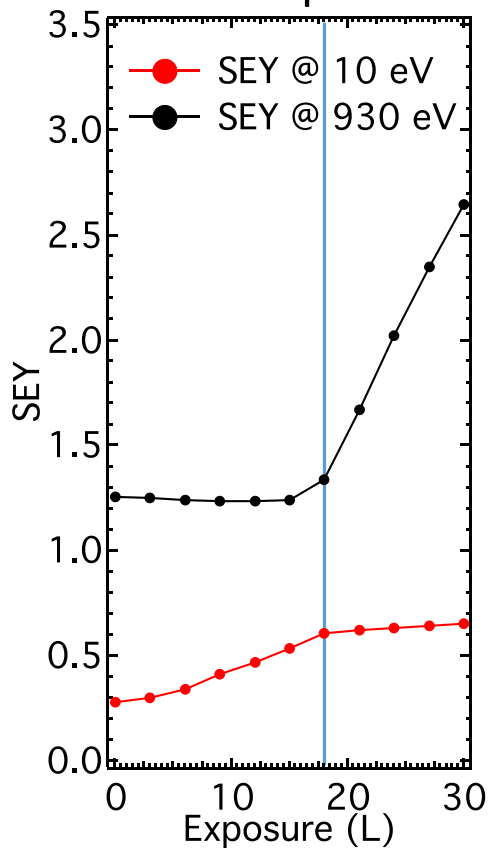


Sample Leaved under continuous scan as function of Time

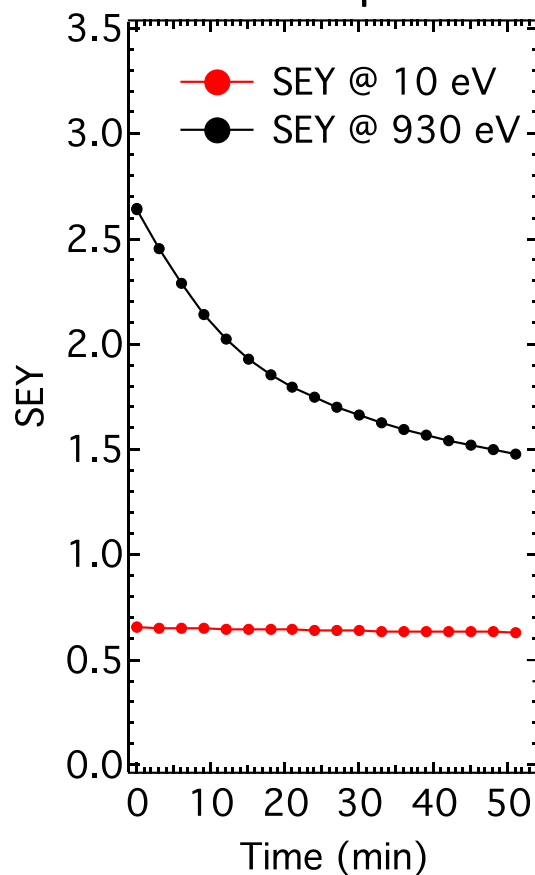


SEY under continuous scan

Adsorption



e^- Desorption

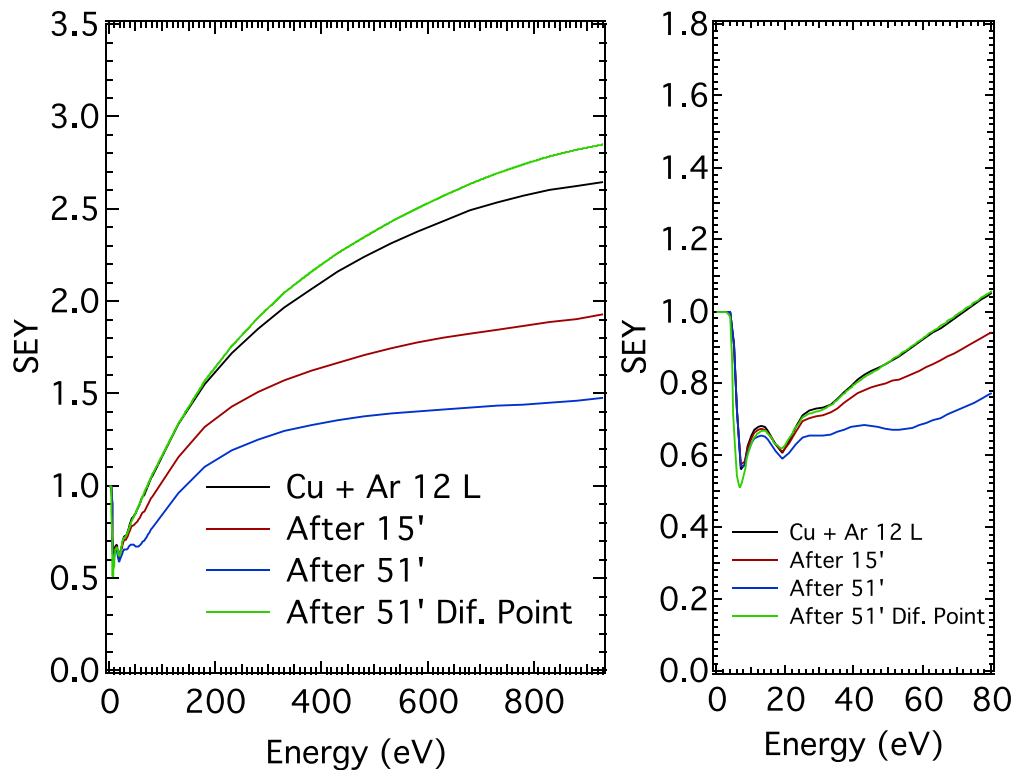


e^- bombardment induced different behaviour

- SEY at 930 decreases as a function of time
- SEY at 10 eV remains constant

e⁻-Argon (SEY)

SEY measured in different points

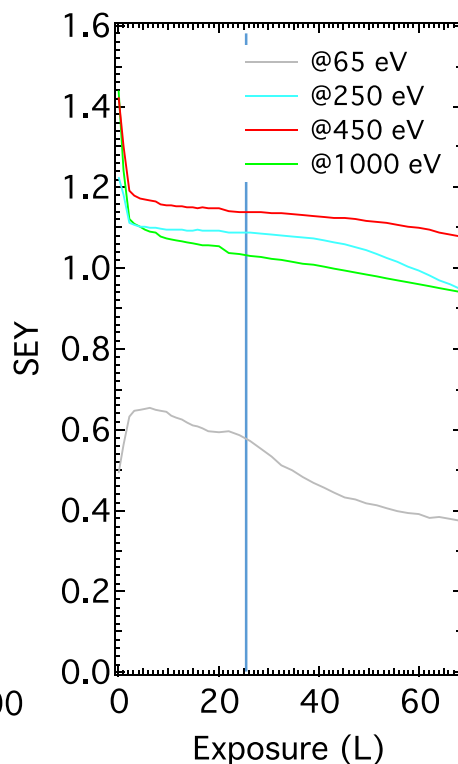
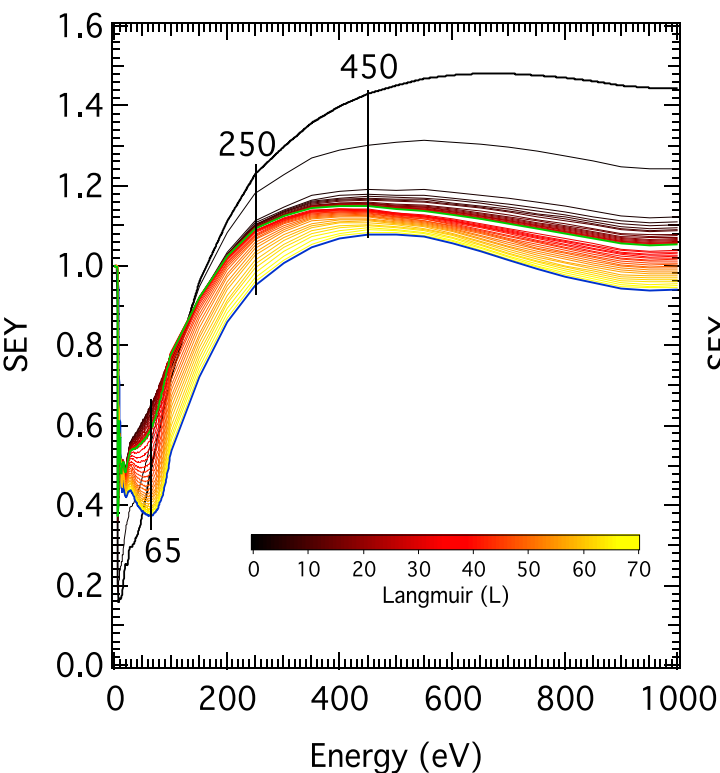


New Point presents different SEY spectra with the same features of SEY with large amount of Ar

Beam-Layer Interaction

Argon Thick film interacts with primary electrons
and *desorbs*

Adsorption process of Carbon Monoxide on Cu sample at 10K General behaviour



Two different regions

High Energy
(>50 eV)

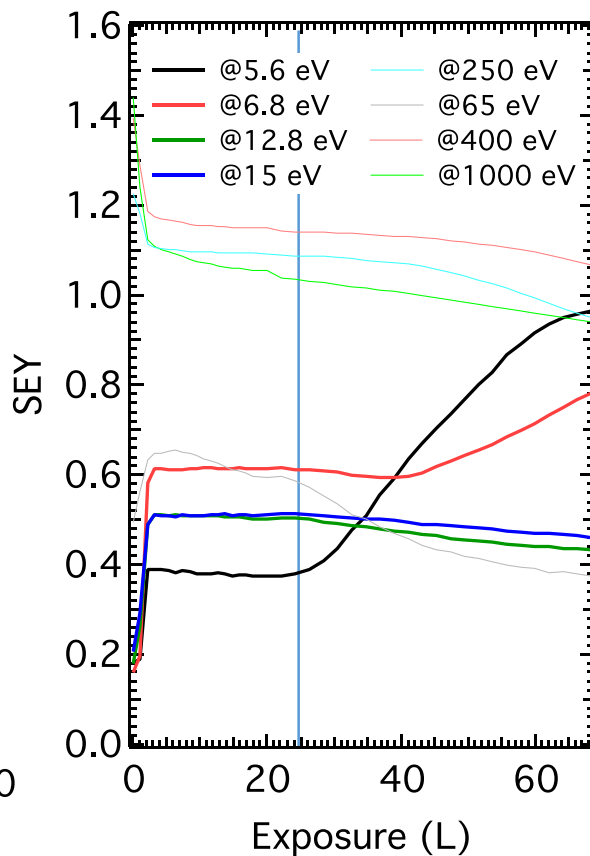
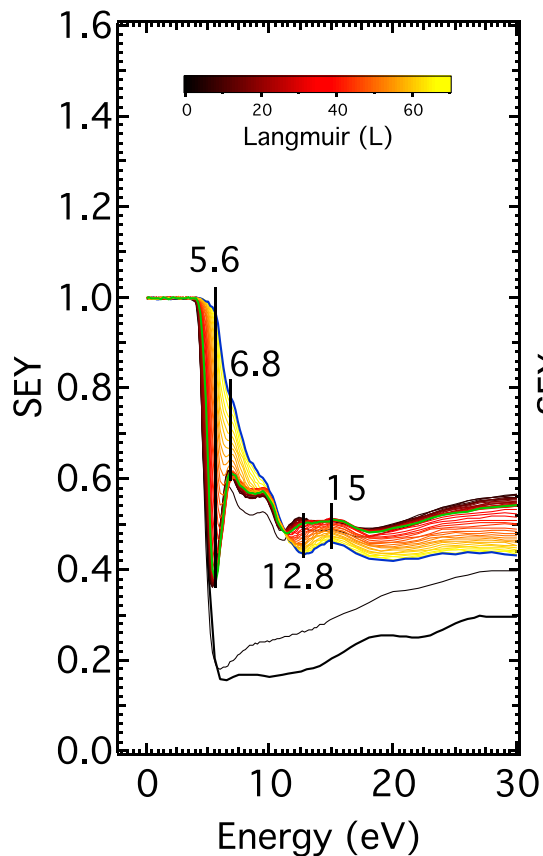
Low Energy
(<50 eV)



- SEY @ 1000 eV decreases during deposition from **1.4** to **1.1**
- Formation of CO Thick Film (TF)
- Characteristic peak of TF at 65 eV

CO Adsorption (SEY)

Adsorption process of Carbon Monoxide on Cu sample at 10K
 Low Energy behaviour



Two different regions

High Energy
(>50 eV)

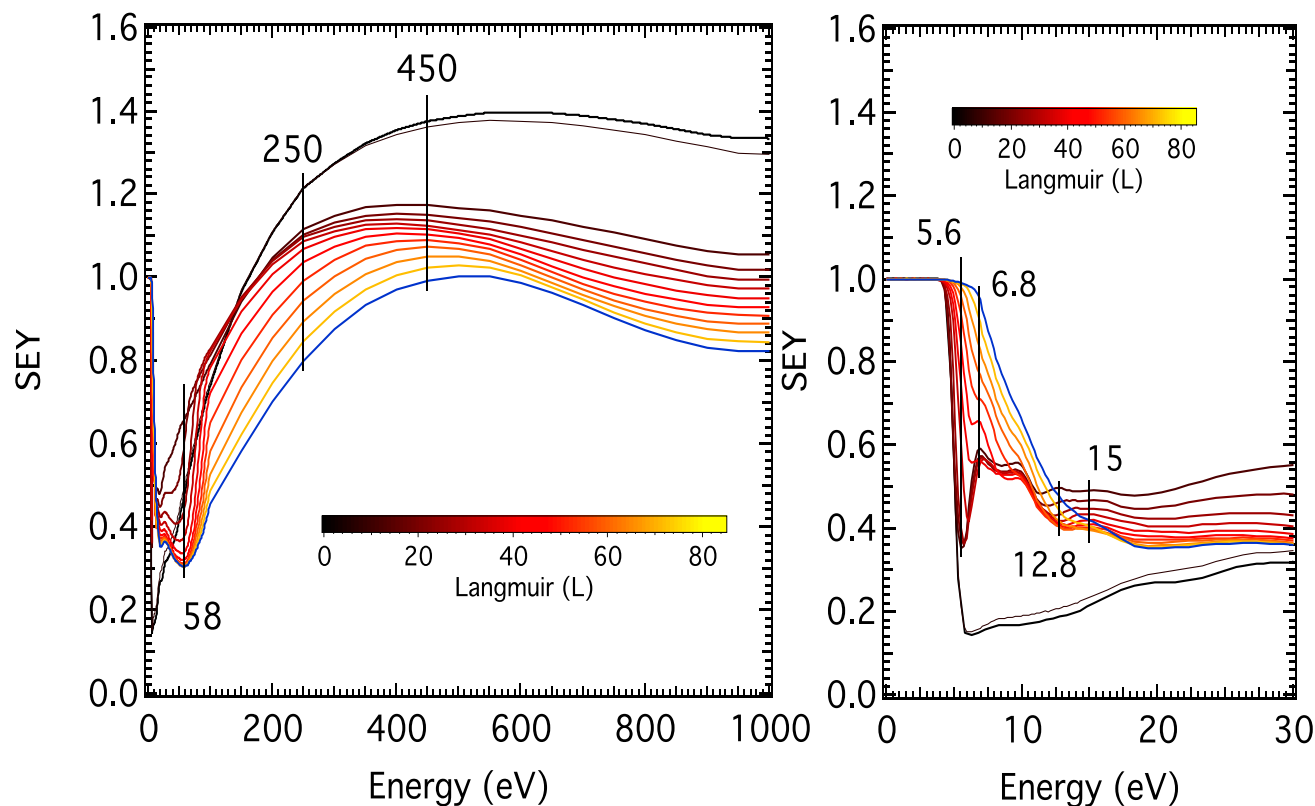
Low Energy
(<50 eV)



- Characteristic peaks at different low energies
- Formation of Argon Single Layer (SL)

CO Adsorption II (SEY)

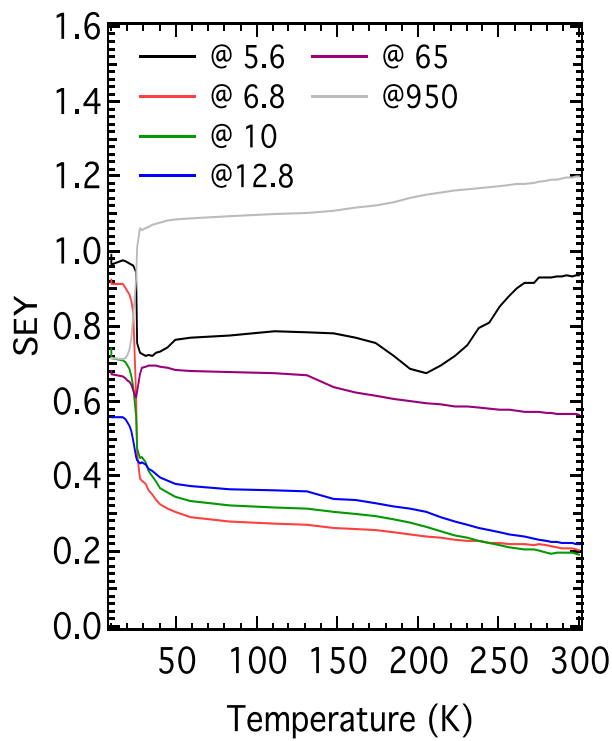
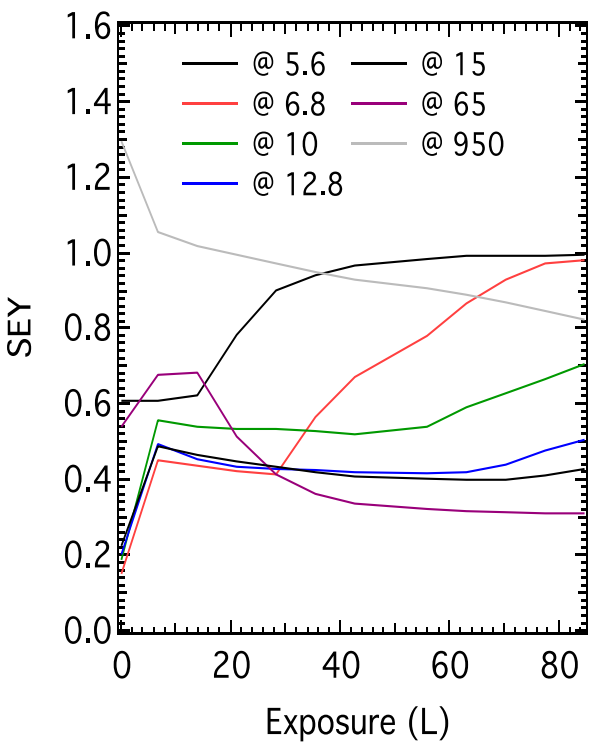
Adsorption process of Carbon Monoxide on Cu sample at 10K
General behaviour



- Higher total Langmuir exposure
- Same characteristic features of TF and SL

CO Desorption (SEY)

Desorption process of Carbon Monoxide on
Cu sample heated up to 300 K
General behaviour



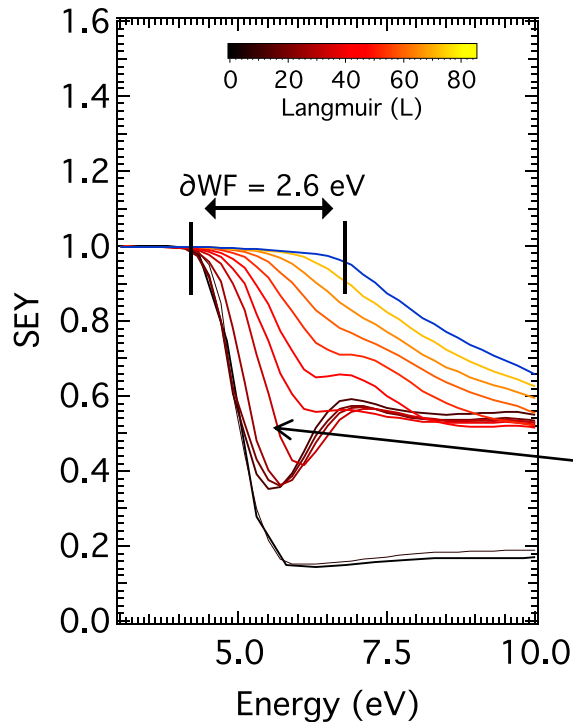
- Not Linear behaviour as in Ar
- Two different Desorption process around 30 K and 200 K respectively

Adsorption Process (10 K)

- Formation of a TF with Low SEY
- Characteristic peaks for SL in the Low Energy Regions

Work Function variation

CO Adsorption



No changes in the first steps of adsorption

Changes after formation of the multi-layer

Important Results

- Follow Adsorption process checking the High-Energy SEY (HE-SEY)
- Distinguish Single Layer (SL) formations from Thick Film (TF) by Low-Energy SEY (LE-SEY) behaviour
- Quantify the numbers of adsorbed gas layers on surface
- Measure the desorption temperature of TF and SL with SEY and TPD
- Measure Work Function (WF) variation

Future Activities

- Different Gases adsorption (CO, CO₂, CH₄ ...) (pure and mixture)
 - Electron desorption
 - Thermal Programmed Desorption (TPD)
-
- Gas-Line Upgrades
 - TPD Upgrades

LNf Lab Upgrades

- Upgrade Gas-line on low temperature system
Low pressure gas dosing in front of sample (with gas line upgrades)

- Upgrade TPD system
Measure of temperature, Heating system, relative position in front of mass spectrometer